

1200 V
Size 40
4" Wafer

Electrical Characteristics (Wafer Form)

Parameter	Description	Guaranteed (Min/Max)	Test Conditions
V_{FM}	Forward Voltage	2.6V Max.	$T_J = 25^{\circ}C$, $I_F = 8.0A$
BV_R	Reverse Breakdown Voltage	1200V Min.	$T_J = 25^{\circ}C$, $I_R = 250\mu A$
I_{RM}	Reverse Leakage Current	20 μA Max.	$T_J = 25^{\circ}C$, $V_R = 1200V$

Mechanical Data

Normal Backmetal Composition, Thickness:	Al-Ti-Ni-Ag (1kA-1kA-4kA-6kA)
Normal Front Metal Composition, Thickness:	99% Al, 1% Si (3 microns)
Dimensions:	0.169" x 0.220"
Wafer Diameter:	100mm, with std. < 100 > flat
Wafer thickness:	.015" + / -.003"
Relevant Die Mechanical Dwg. Number	01-5157
Minimum Street Width	100 Microns
Reject Ink Dot Size	0.25mm Diameter Minimum
Ink Dot Location	See Die Outline drawing below
Recommended Storage Environment:	Store in original container, in dessicated nitrogen, with no contamination

Reference Standard IR packaged part (for design) : HFA16PB120

Die Outline

